

IEC SYSTEM FOR MUTUAL RECOGNITION OF TEST CERTIFICATES FOR ELECTRICAL EQUIPMENT (IECEE)
CB SCHEME

CB TEST CERTIFICATE

Product

Intel® NUC

Name and address of the applicant

INTEL CORPORATION
2200 MISSION COLLEGE BLVD SANTA CLARA, CA 95054-1537 USA

Name and address of the manufacturer

INTEL CORPORATION
2200 MISSION COLLEGE BLVD SANTA CLARA, CA 95054-1537 USA

Name and address of the factory

Note: When more than one factory, please report on page 2

GOLDEN ELITE TECHNOLOGY (SHEN ZHEN) LTD
1 NAN HUAN RD SHAJING BAO AN SHENZHEN
GUANGDONG 518104
CHINA Additional Information on page 2

Ratings and principal characteristics

- 1) 19 Vdc , 3.43 A or 19 Vdc , 3.42 A
- 2) 19 Vdc , 3.42 A
- 3) 19 Vdc , 4.74 A

Trademark (if any)



Type of Customer's Testing Facility (CTF) Stage used

Model / Type Ref.

xNUC6xAyX, xNUC7xBNHx, xNUC7xBNKx, xNUC7xJYx,
xNUC8xBEHx, xNUC8xBEKx
See Page 2

Additional information (if necessary may also be reported on page 2)

Technical modification

 Additional Information on page 2

A sample of the product was tested and found to be in conformity with

IEC 60950-1:2005/AMD1:2009, IEC 60950-1:2005/AMD2:2013,
IEC 60950-1:2005

As shown in the Test Report Ref. No. which forms part of this Certificate

ATTCB106089-03 issued on 2018-12-04

This CB Test Certificate is issued by the National Certification Body



- UL (US), 333 Pfingsten Rd IL 60062, Northbrook, USA
- UL (Demko), Borupvang 5A DK-2750 Ballerup, DENMARK
- UL (JP), Marunouchi Trust Tower Main Building 6F, 1-8-3 Marunouchi, Chiyoda-ku, Tokyo 100-0005, JAPAN
- UL (CA), 7 Underwriters Road, Toronto, M1R 3B4 Ontario, CANADA

For full legal entity names see www.ul.com/ncbnames

Date: 2018-12-06

Signature:

Original Issue Date: 2018-01-09

Jan-Erik Storgaard



Ref. Certif. No.

DK-69732-M3-UL

Model Details:

1) xNUC6xAyX, xNUC7xBNHx, xNUC7xBNKx

2) xNUC7xJYx

3) xNUC8xBEHx, xNUC8xBEKx

(where x can be a combination of alphanumeric characters, none or blank)

Additional Information:

Additionally evaluated to EN 60950-1:2006 /A11:2009 /A1:2010 /A12:2011 /A2:2013; National Differences specified in the CB Test Report.

The original report was modified to include the following changes/additions:

- add two alternative sources of power adapter for model xNUC8xBEHx, xNUC8xBEKx.
- modify the description for External Enclosure in table 1.5.1.

Additional information (if necessary)



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